IRF7316TRPBF-VB Datasheet

Dual P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY			
V_{DS} (V)	$R_{DS(on)}$ (Ω)	I_D (A)[d, e]	Q_g (Typ.)
- 30	0.035 at V_{GS} = - 10 V	- 7.3	17 nC
	0.045 at V_{GS} = - 4.5 V	- 6.3	

FEATURES

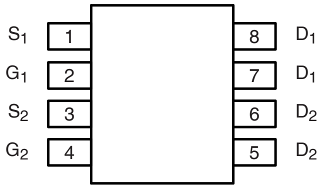
- **Halogen-free**
- Trench Power MOSFET
- 100 % UIS Tested

Pb-free
RoHS
COMPLIANT

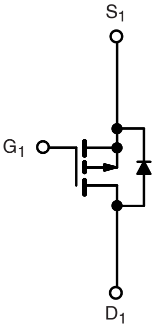
APPLICATIONS

- Load Switches

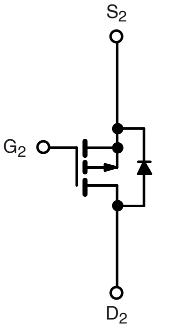
SO-8



Top View



P-Channel MOSFET



P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T_A = 25 °C, unless otherwise noted				
Parameter		**Symbol**	**Limit**	**Unit**
Drain-Source Voltage		V_{DS}	- 30	V
Gate-Source Voltage		V_{GS}	± 20	
Continuous Drain Current (T_J = 150 °C)	T_C = 25 °C	I_D	- 7.3[e]	A
	T_C = 70 °C		- 7.0[e]	
	T_A = 25 °C		- 7.3[a, b]	
	T_A = 70 °C		- 5.9[a, b]	
Pulsed Drain Current		I_{DM}	- 32[e]	
Continuous Source-Drain Diode Current	T_C = 25 °C	I_S	- 4.1	
	T_A = 25 °C		- 2.0[a, b]	
Avalanche Current	L = 0.1 mH	I_{AS}	- 20	
Single-Pulse Avalanche Energy		E_{AS}	20	mJ
Maximum Power Dissipation	T_C = 25 °C	P_D	5.0	W
	T_C = 70 °C		3.2	
	T_A = 25 °C		2.5[a, b]	
	T_A = 70 °C		1.6[a, b]	
Operating Junction and Storage Temperature Range		T_J, T_{stg}	- 55 to 150	°C

THERMAL RESISTANCE RATINGS					
Parameter		**Symbol**	**Typical**	**Maximum**	**Unit**
Maximum Junction-to-Ambient[a, c]	t ≤ 10 s	R_{thJA}	38	50	°C/W
Maximum Junction-to-Foot	Steady State	R_{thJF}	20	25	

Notes:
a. Surface mounted on 1" x 1" FR4 board.
b. t = 10 s.
c. Maximum under Steady State conditions is 85 °C/W.
d. Based on T_C = 25 °C.
e. Limited by package.

SPECIFICATIONS T_J = 25 °C, unless otherwise noted

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0$ V, $I_D = -250$ µA	- 30			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = -250$ µA		- 31		mV/°C
$V_{GS(th)}$ Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			4.5		
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = -250$ µA	- 1.0		- 3.0	V
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0$ V, $V_{GS} = \pm 20$ V			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -30$ V, $V_{GS} = 0$ V			- 1	µA
		$V_{DS} = -30$ V, $V_{GS} = 0$ V, $T_J = 55$ °C			- 5	
On-State Drain Current[a]	$I_{D(on)}$	$V_{DS} \geq -10$ V, $V_{GS} = -10$ V	- 30			A
Drain-Source On-State Resistance[a]	$R_{DS(on)}$	$V_{GS} = -10$ V, $I_D = -6.3$ A		0.035		Ω
		$V_{GS} = -4.5$ V, $I_D = -6.2$ A		0.040		
Forward Transconductance[a]	g_{fs}	$V_{DS} = -10$ V, $I_D = -6.1$ A		23		S
Dynamic[b]						
Input Capacitance	C_{iss}	$V_{DS} = -15$ V, $V_{GS} = 0$ V, f = 1 MHz		1350		pF
Output Capacitance	C_{oss}			215		
Reverse Transfer Capacitance	C_{rss}			185		
Total Gate Charge	Q_g	$V_{DS} = -15$ V, $V_{GS} = -10$ V, $I_D = -6.1$ A		32	50	nC
		$V_{DS} = -15$ V, $V_{GS} = -4.5$ V, $I_D = -6.1$ A		15	25	
Gate-Source Charge	Q_{gs}			4		
Gate-Drain Charge	Q_{gd}			7.5		
Gate Resistance	R_g	f = 1 MHz		5.8		Ω
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -15$ V, $R_L = 15$ Ω $I_D \cong -1$ A, $V_{GEN} = -10$ V, $R_g = 1$ Ω		10	15	ns
Rise Time	t_r			8	15	
Turn-Off DelayTime	$t_{d(off)}$			45	70	
Fall Time	t_f			12	25	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -15$ V, $R_L = 15$ Ω $I_D \cong -1$ A, $V_{GEN} = -4.5$ V, $R_g = 1$ Ω		42	70	
Rise Time	t_r			35	60	
Turn-Off DelayTime	$t_{d(off)}$			40	70	
Fall Time	t_f			16	30	
Drain-Source Body Diode Characteristics						
Continous Source-Drain Diode Current	I_S	$T_C = 25$ °C			- 4.1	A
Pulse Diode Forward Current	I_{SM}				- 32	
Body Diode Voltage	V_{SD}	$I_S = -2$ A, $V_{GS} = 0$ V		- 0.75	- 1.2	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F = -2$ A, dI/dt = 100 A/µs, $T_J = 25$ °C		34	60	ns
Body Diode Reverse Recovery Charge	Q_{rr}			22	40	nC
Reverse Recovery Fall Time	t_a			11		ns
Reverse Recovery Rise Time	t_b			23		

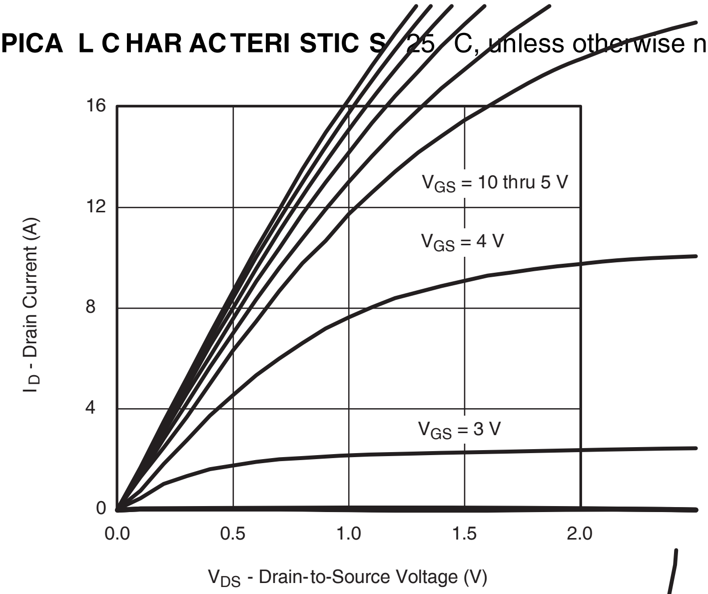
Notes:

a. Pulse test; pulse width ≤ 300 µs, duty cycle ≤ 2 %.

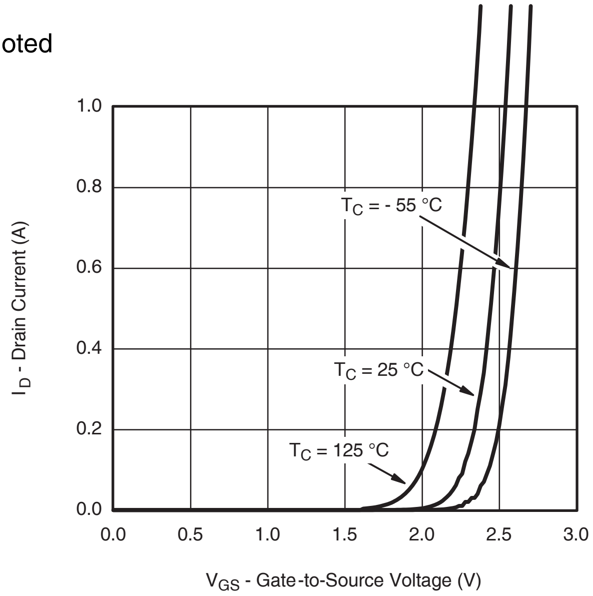
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

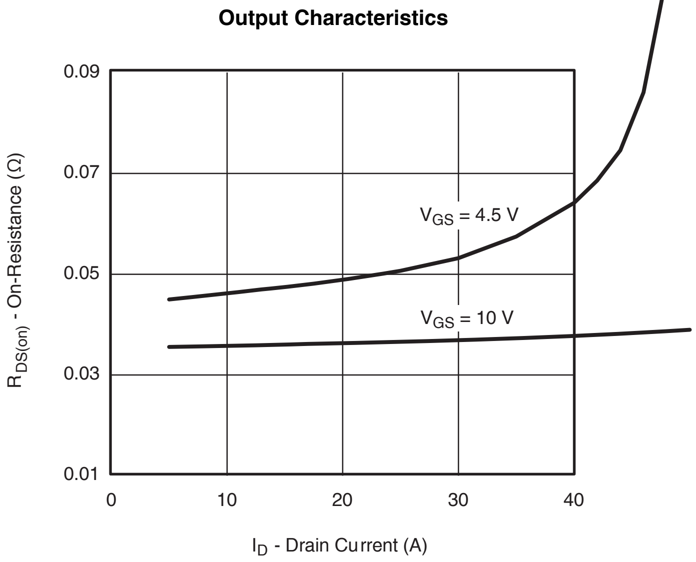
TYPICAL CHARACTERISTICS 25 C, unless otherwise noted



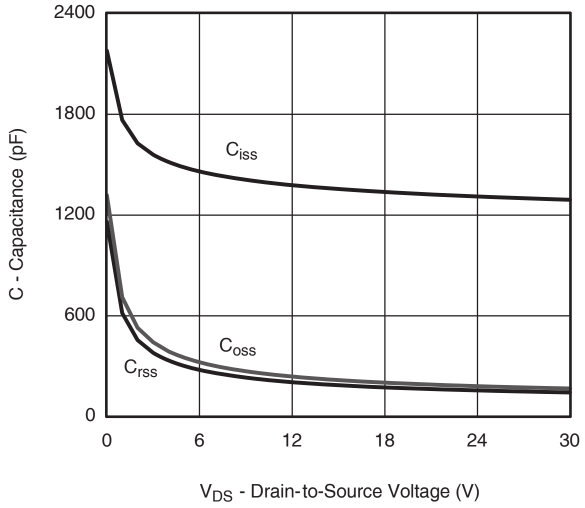
Output Characteristics



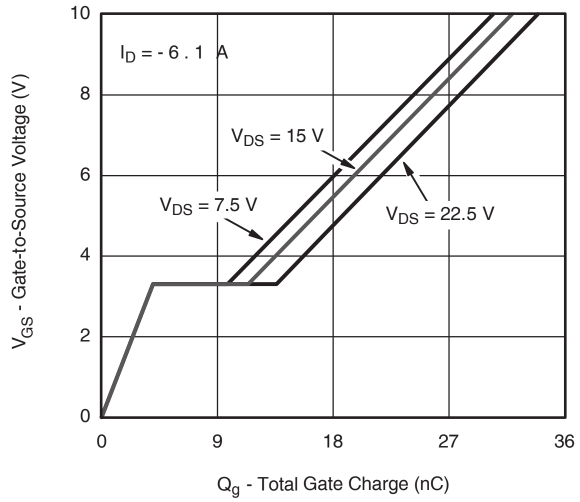
Transfer Characteristics



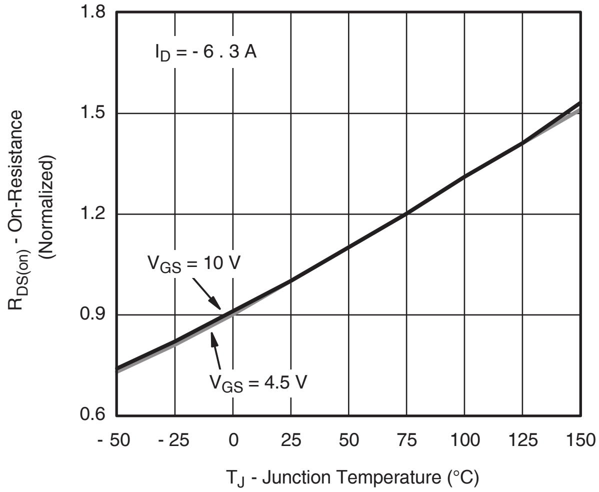
On-Resistance vs. Drain Current



Capacitance

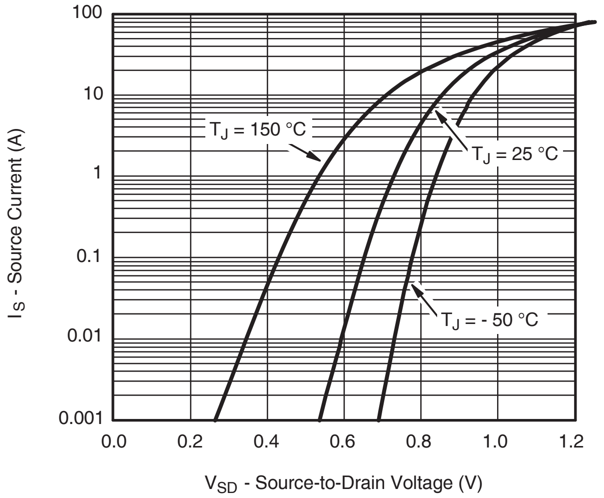


Gate Charge

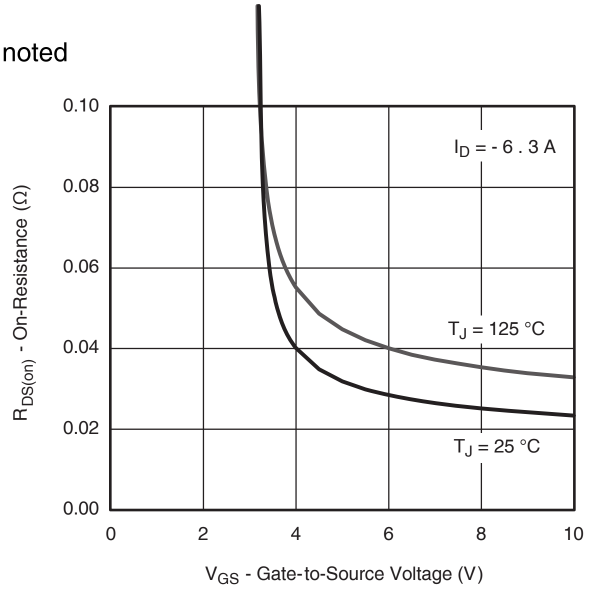


On-Resistance vs. Junction Temperature

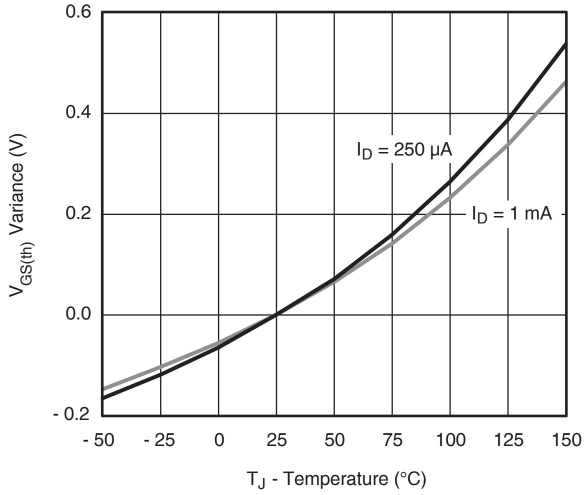
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



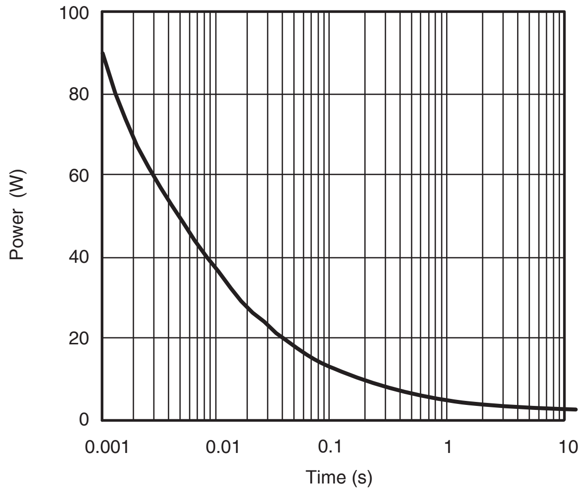
Source-Drain Diode Forward Voltage



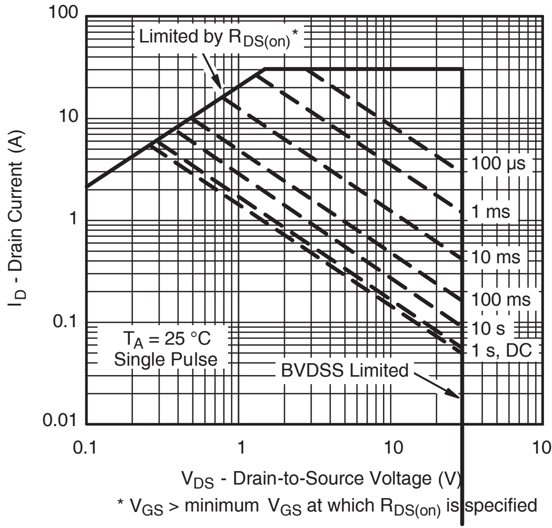
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage



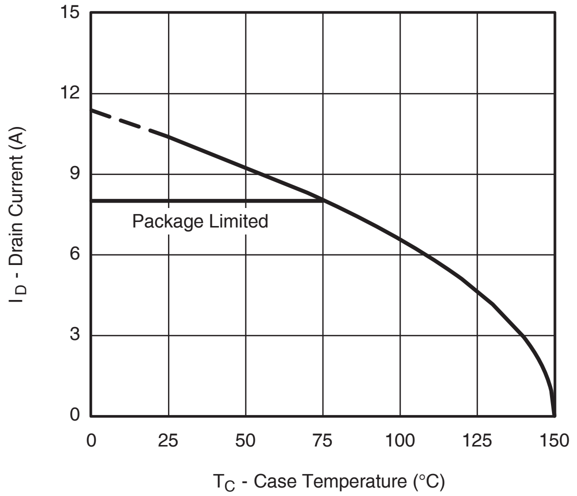
Single Pulse Power, Junction-to-Ambient



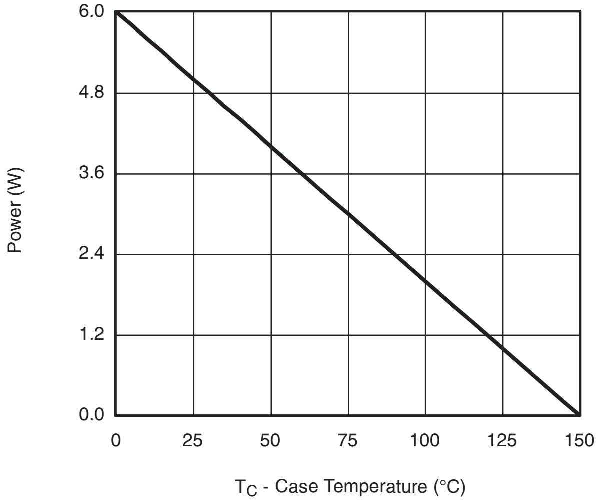
* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area

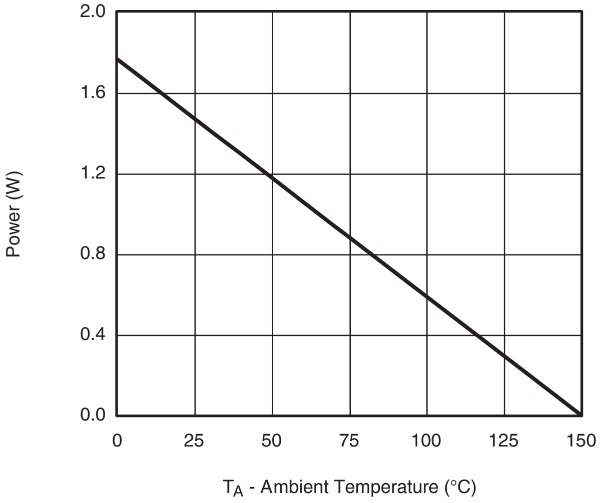
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Current Derating*



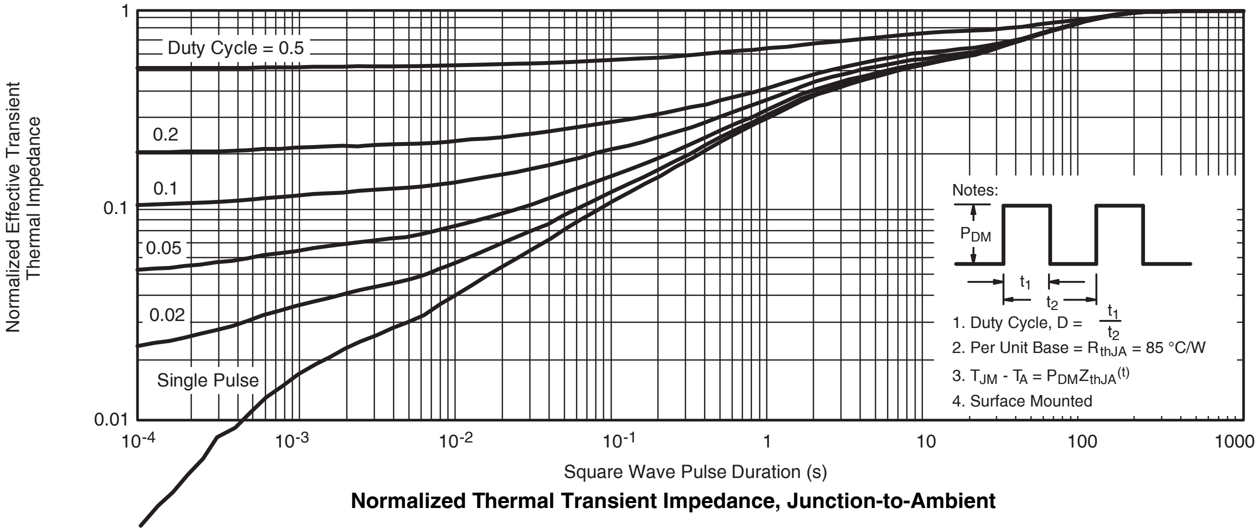
Power, Junction-to-Foot



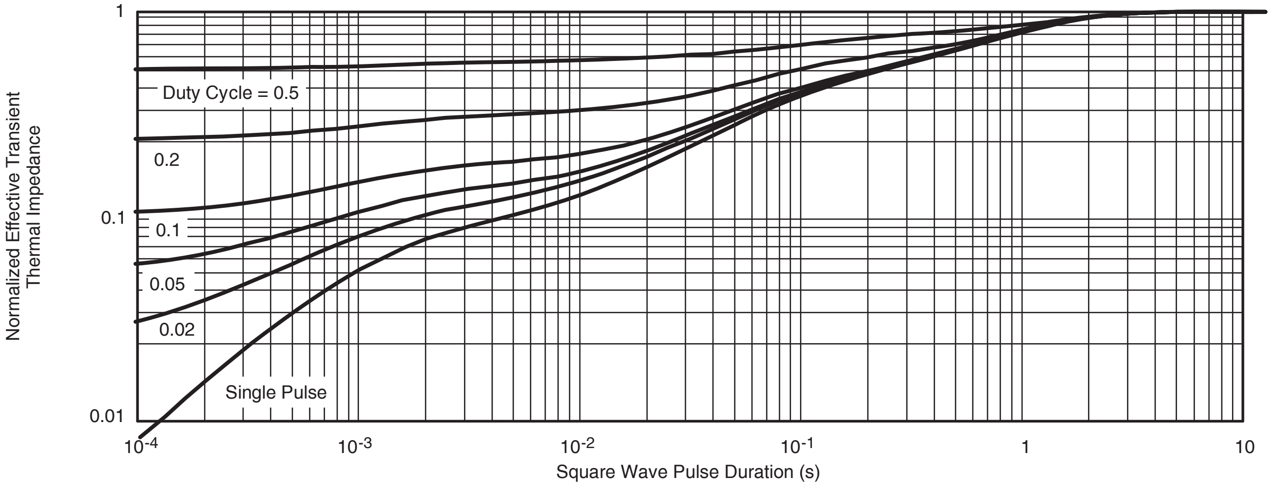
Power Derating, Junction-to-Ambient

* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



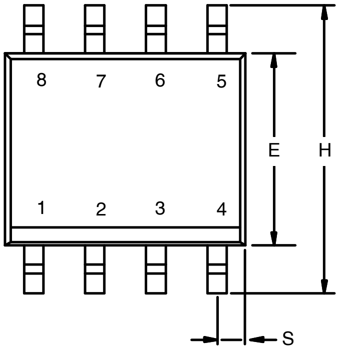
Normalized Thermal Transient Impedance, Junction-to-Ambient

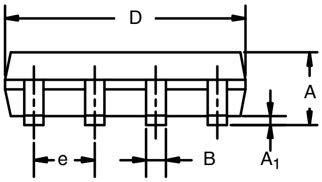


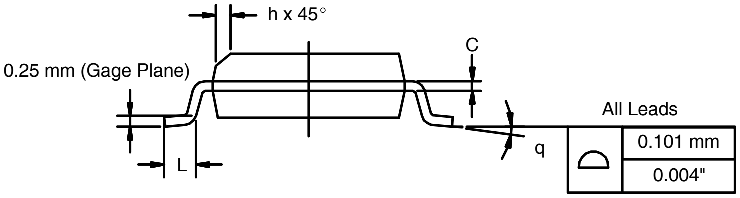
Normalized Thermal Transient Impedance, Junction-to-Foot

SOIC (NARROW): 8-LEAD

JEDEC Part Number: MS-012

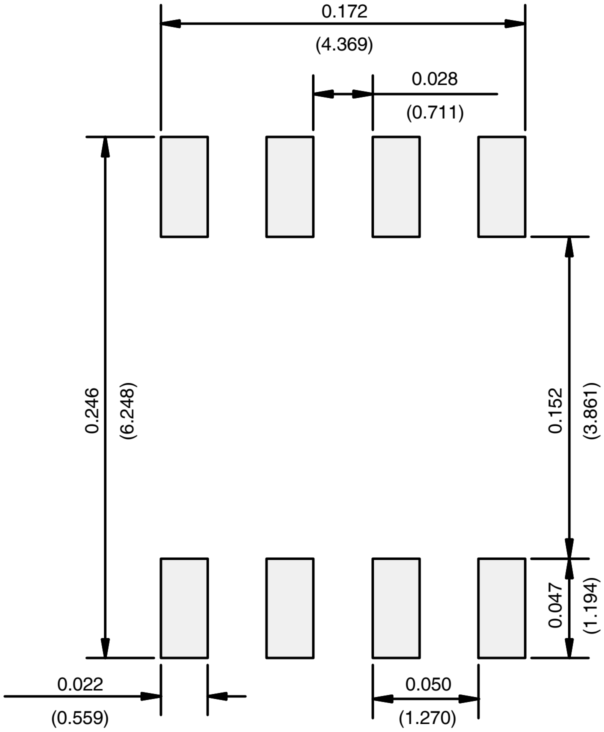






DIM	MILLIMETERS		INCHES	
	Min	Max	Min	Max
A	1.35	1.75	0.053	0.069
A_1	0.10	0.20	0.004	0.008
B	0.35	0.51	0.014	0.020
C	0.19	0.25	0.0075	0.010
D	4.80	5.00	0.189	0.196
E	3.80	4.00	0.150	0.157
e	1.27 BSC		0.050 BSC	
H	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.020
L	0.50	0.93	0.020	0.037
q	0°	8°	0°	8°
S	0.44	0.64	0.018	0.026
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498				

RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads
Dimensions in Inches/(mm)